cleaning critical surfaces

PolyCHECK® Wipers & Swabs



Description

PolyCHECK® Wipers and Swabs are designed to allow engineers and technicians to validate the cleanliness of critical surfaces. PolyCHECK® Wipers are fabricated from a black fabric in order to enable the identification of white or opaque colored particles. PolyCHECK® Swabs employ a white fabric on one side and a black fabric on the other side in order to give clean room professionals a unique particle detection tool. Ideal when used in conjunction with SEM Analysis.

Advantages

- Eliminates the need to contact SEM stubs and tape to critical chamber surfaces.
- Allows for faster analysis of particle sources during tool excursion events.
- Perfect for defect analysis involving SEM stubs.



Applications

- ◆ Ideal for Go/No Go validation checks in vacuum maintainence procedures.
- Excellent general purpose cleanroom wiper for Semiconductor, Medical Device, FPD and Hard Disk Drive manufacturers.
- PolyCHECK®Swabs enable frequent inspections to monitor for particles that may back scatter into process chambers.

Part Numbers

Part No.	Description	Size	Bag/Case Qty
HT5291K-5	PolyCHECK® Wiper	9" x 9"	5/Bag, 200 Bags/Cs
HT5291K	PolyCHECK [®] Wiper	9" x 9"	50/Bag, 24 Bags/Cs
HT1501FCW-5	PolyCHECK [®] Swab	6" Flexible Paddle Tip	5/Bag, 100 Bags/Cs
HT1501FZW-5	PolyCHECK [®] Swab	6" Paddle Tip	5/Bag, 100 Bags/Cs
HT1587FZW-5	PolyCHECK [®] Swab	5" Square Tip	5/Bag, 100 Bags/Cs





<u>Wiper</u>



HT1501FCW - PolyCHECK™ Swab

<u>Swab</u>

Particle	generation via	I PC

Specifications

Cleanliness

neration via LPC >.5 micron

>.5 micron >.5 micron

>.3micron particles/m ²	1500 particles/cm ²	<700 particles/Tip

Ion Count of Extractibles	PPM	Micrograms/Tip
Sulfate	<.05	<.8
Chloride	<.05	<.9
Fluoride	<.02	<.02

Non-Volatile Residue (g/m²)

DI Water	<.5	<.3
IPA	<1.5mg/g	<1

Silicon/Amide Free Pass

Absorptive Capacity Specifications

Basis Weight (g/m²)	120
Absorbency (ml/m²)	190
Absorptive Rate (ml/g)	3.2

